

Non-linear effects in silicon photonic devices: modelling and experiments

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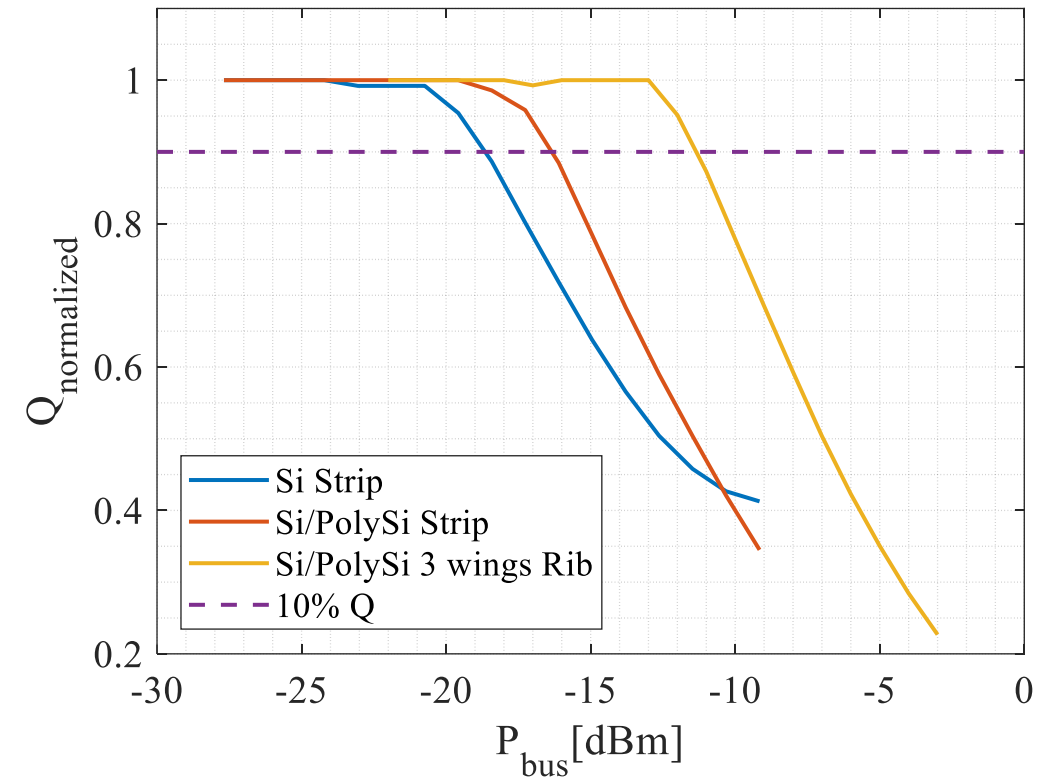
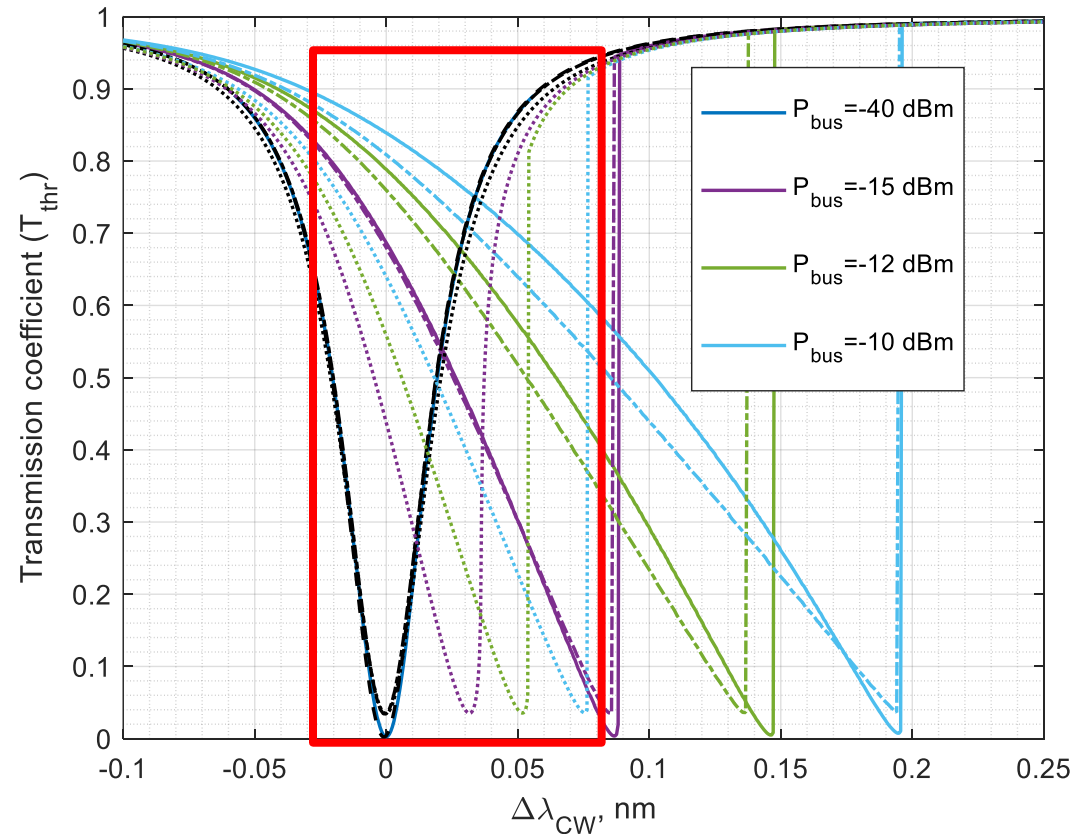


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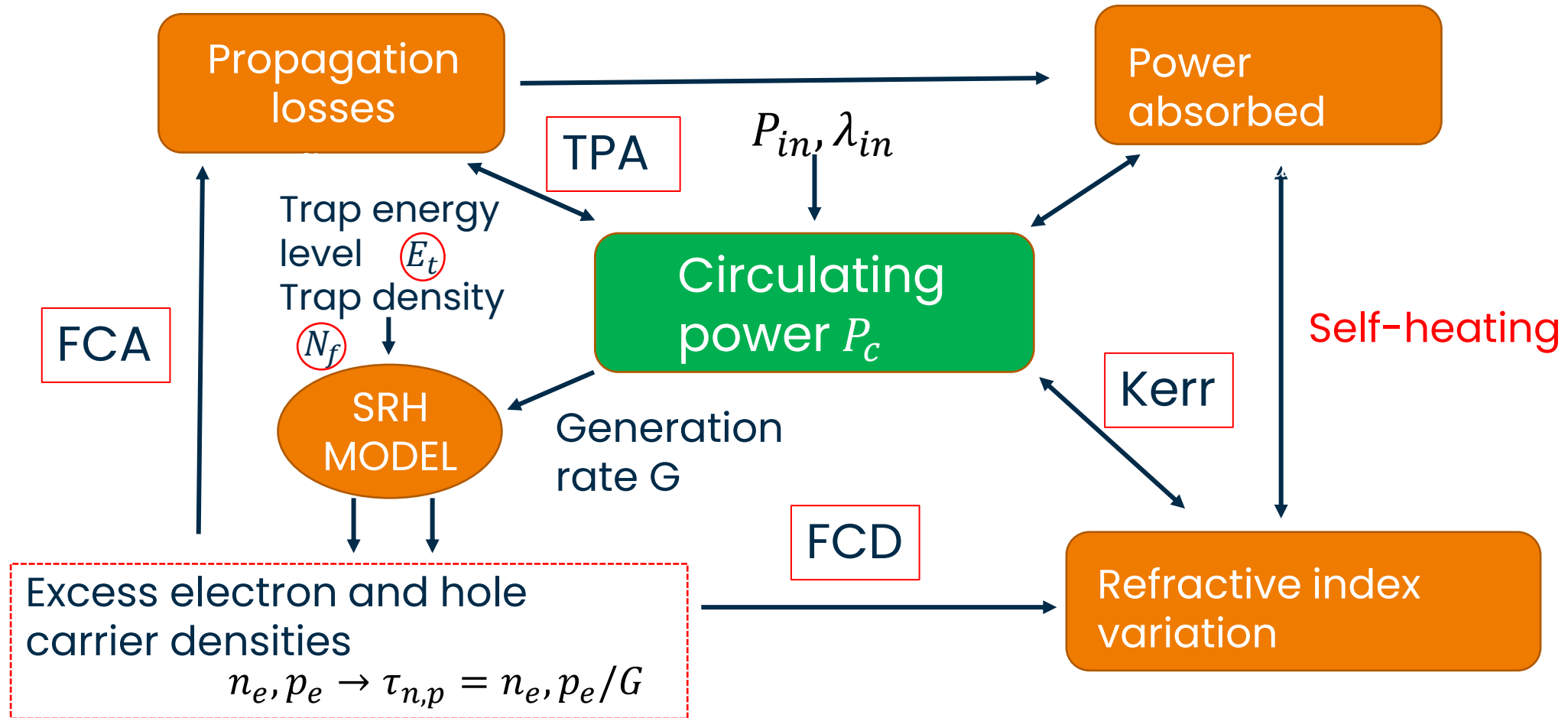
Modelling results



Transmission spectra of the 3 MRRs at different bus input power:

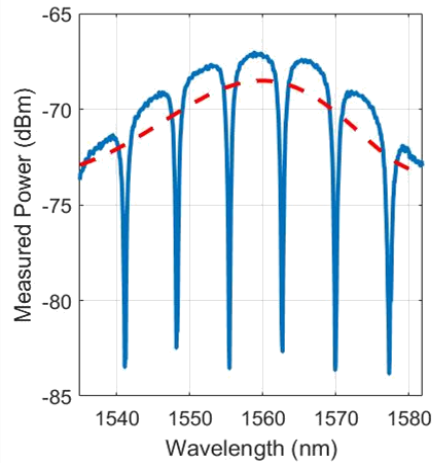
- Si strip (continuous)
- Si/PolySi strip (dash-dotted)
- **Si/PolySi 3 wings Rib guide** (dotted)

Si non linear model

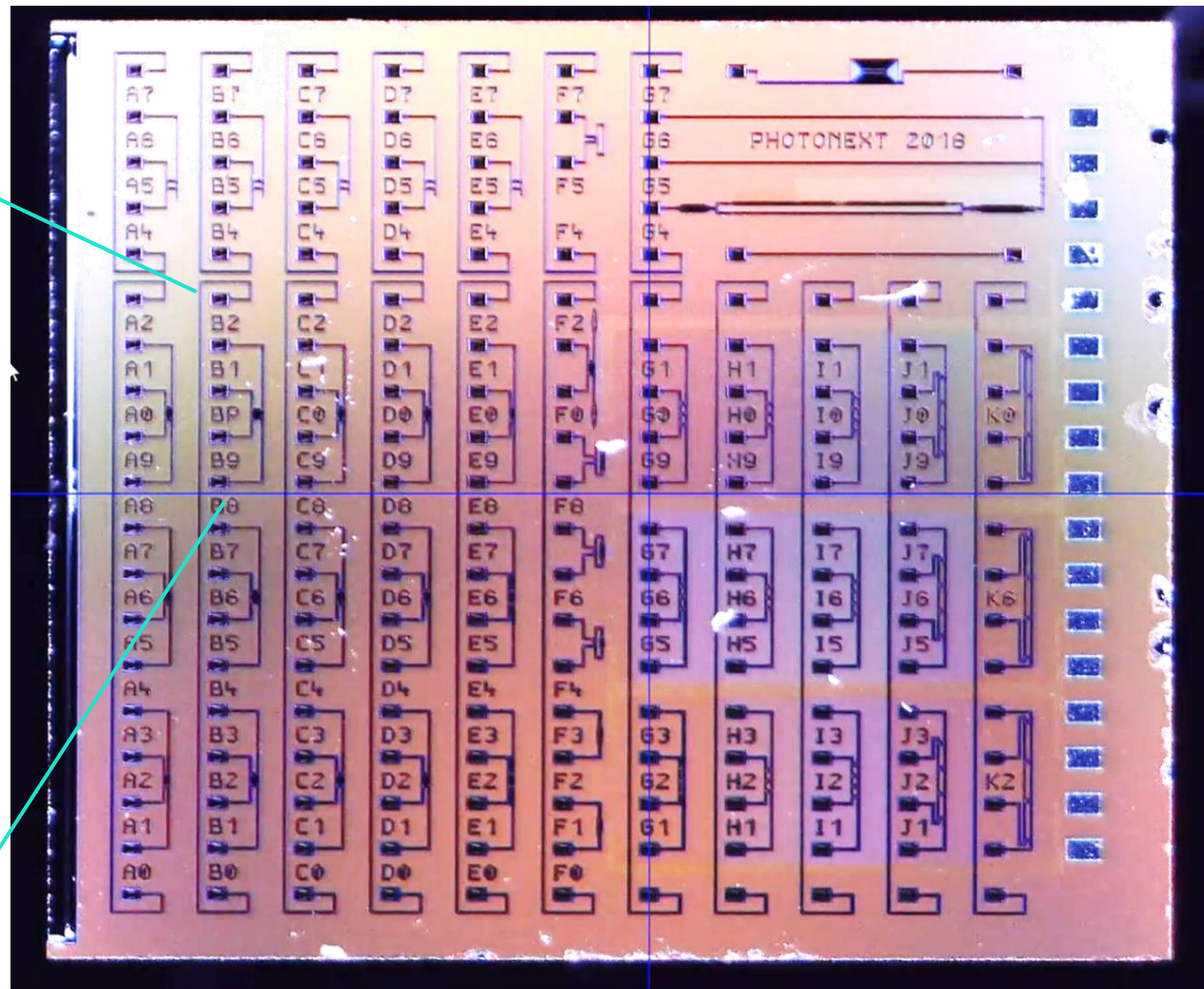
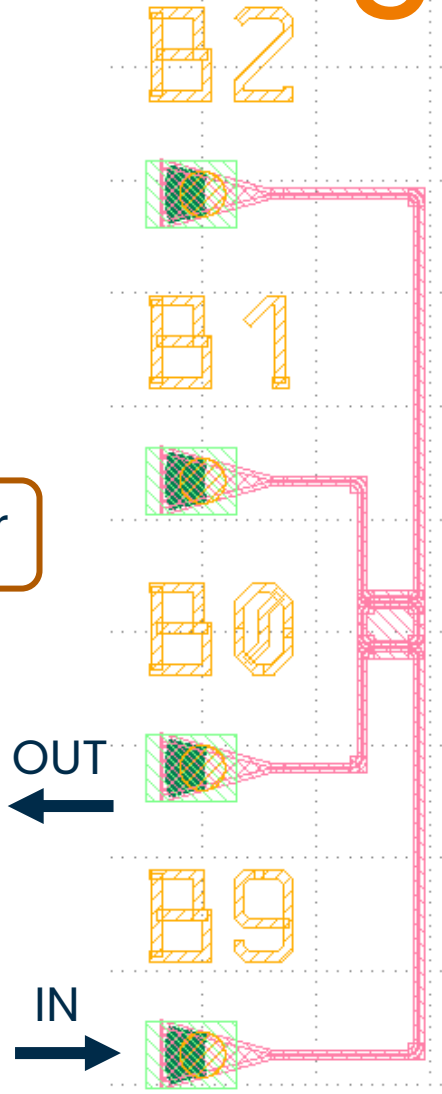
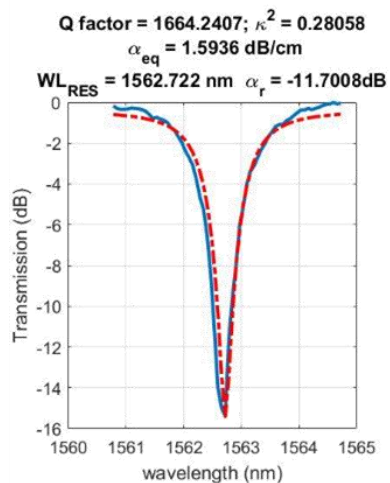


Si ring resonator

Low power spectrum

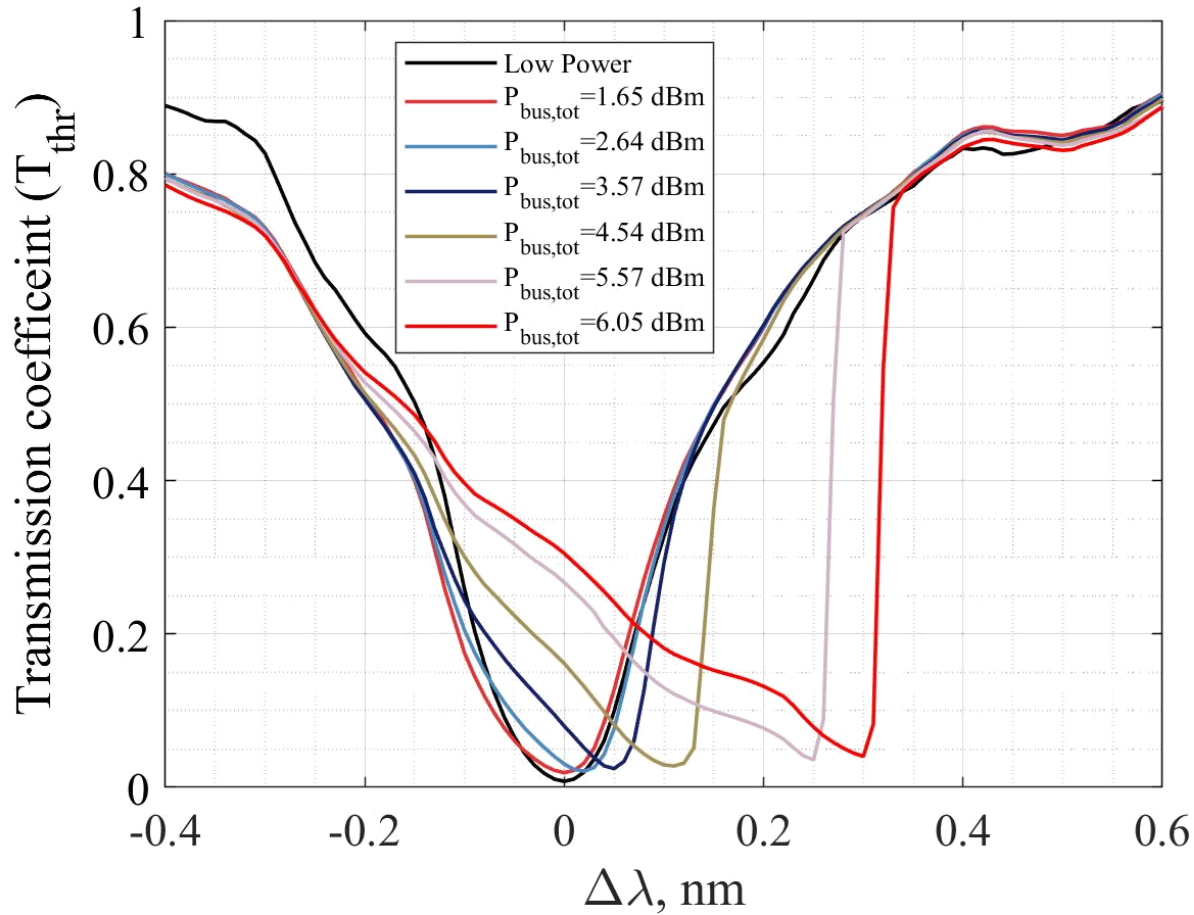


Extract ring parameter

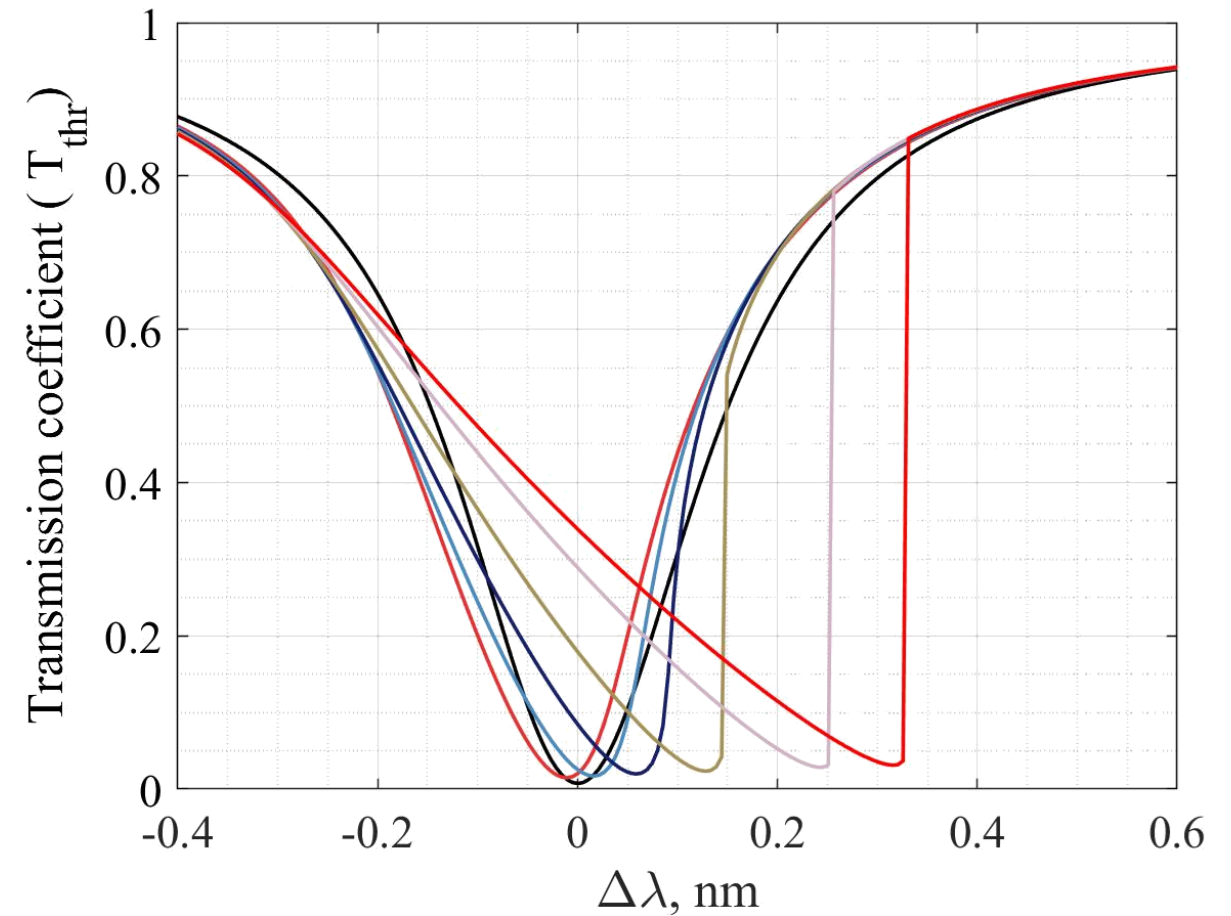


Experiment vs model

Experiment

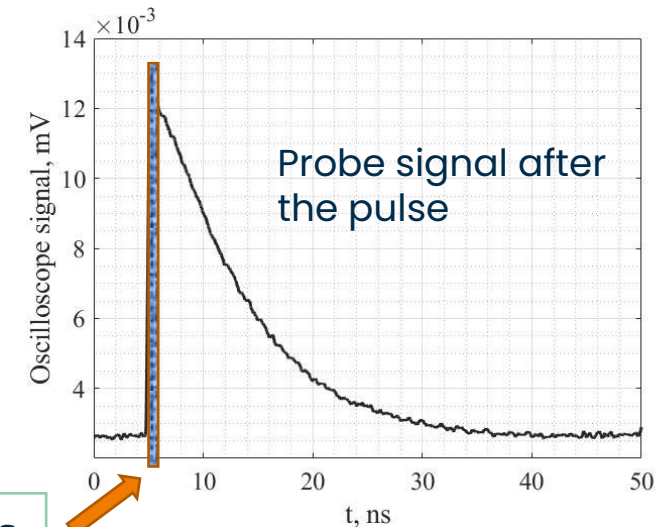
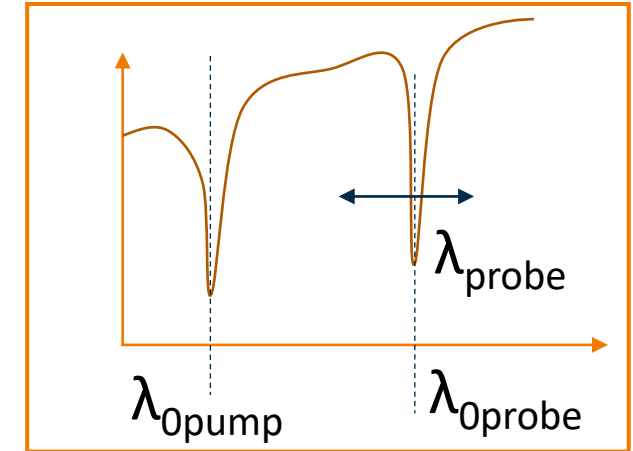
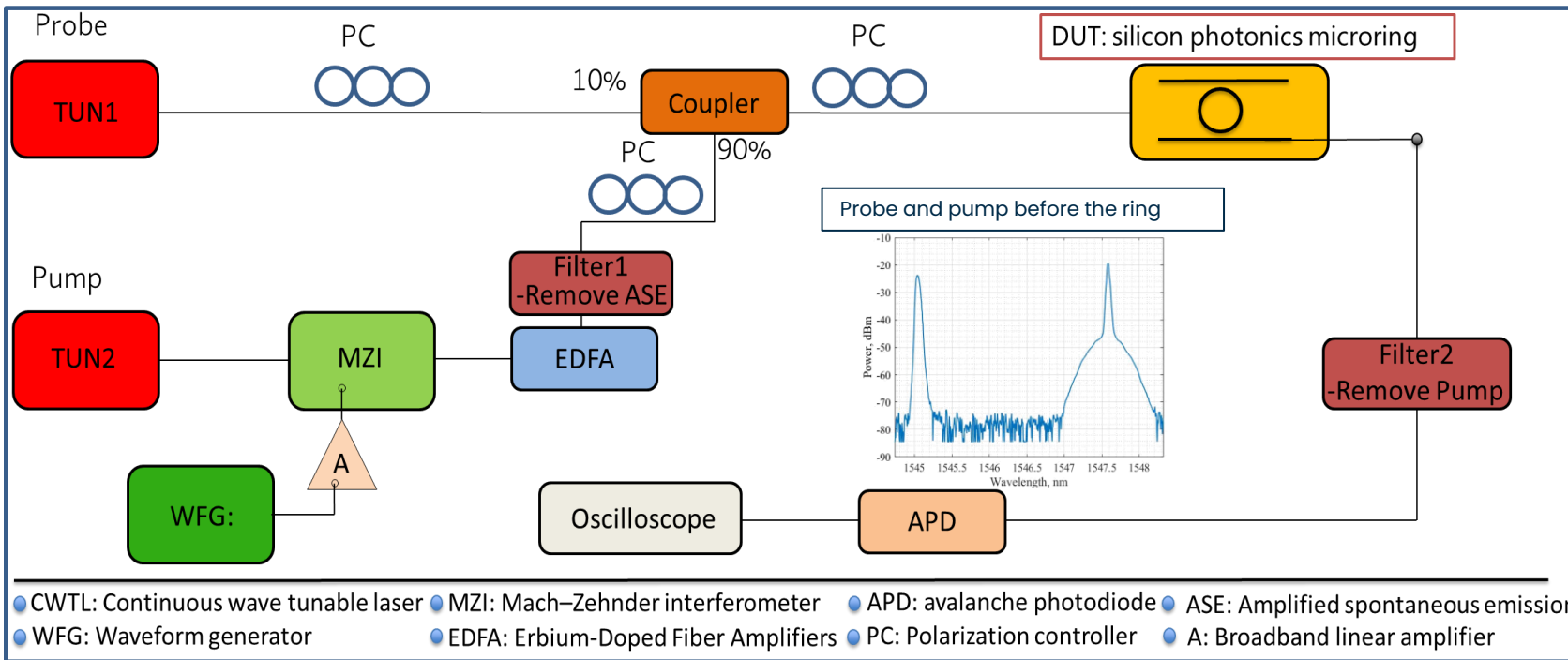


Model



Marco Novarese, Sebastian Romero-García, Don Adams, Jock Bovington, Mariangela Gioannini, "Study of nonlinear effects and self-heating in a silicon microring resonator including a Shockley-Read-Hall model for carrier recombination," Opt. Express 30, 14341-14357, 2022.

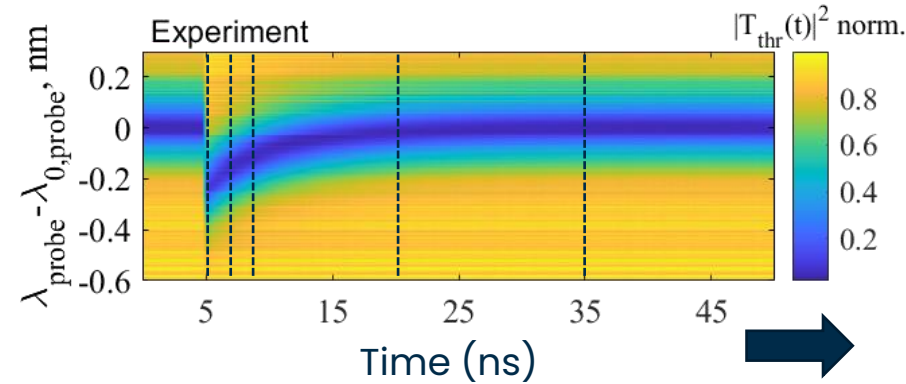
Pump-probe setup



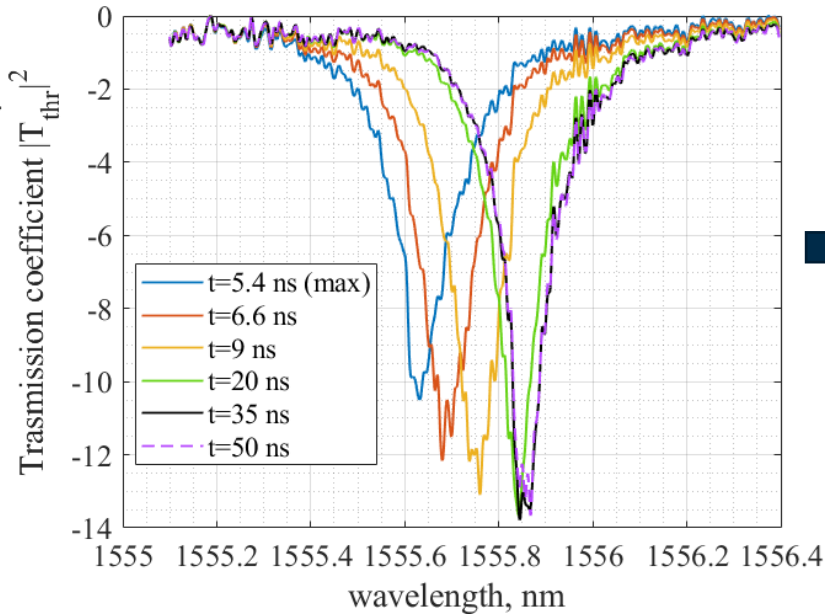
Pump pulse width = 100ps

Pump-probe experimental results

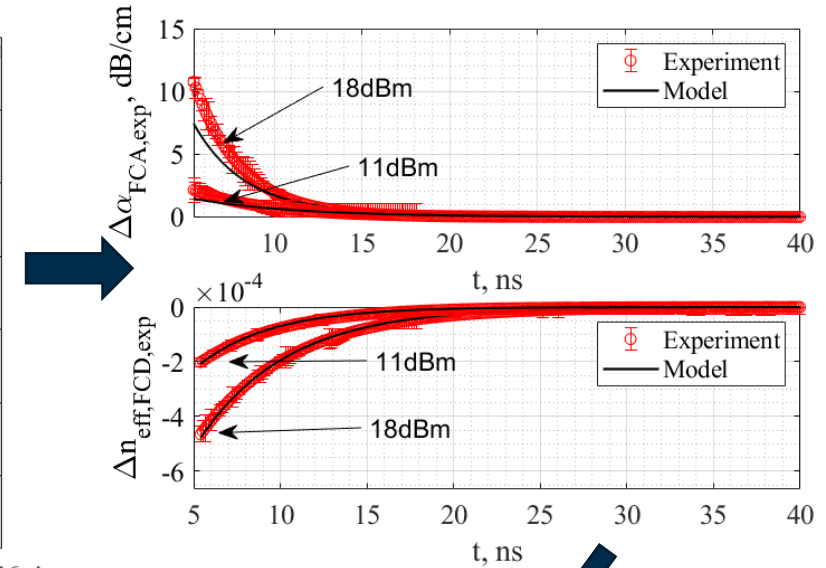
Map of probe signals (at different wavelengths) vs time



Time resolved transmission spectra



Recovery of absorption and refractive index variation



Electro-absorption/refraction relations in silicon

$$\Delta\alpha_{FCA} = \Gamma(8.8 \cdot 10^{-21} n_e^{1.167} + 5.84 \cdot 10^{-20} p_e^{1.109})$$

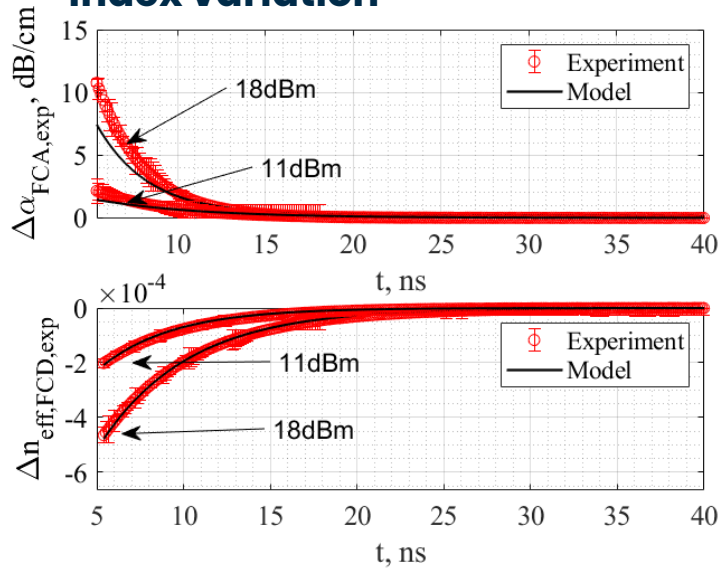
$$\Delta n_{eff,FCD} = -\Gamma(5.4 \cdot 10^{-22} n_e^{1.011} + 1.53 \cdot 10^{-18} p_e^{0.838})$$

Extraction of electrons and holes free carrier densities

Nedeljkovic, M., Soref, R., and Mashanovich, G. Z., *IEEE Photonics Journal*, 3(6):1171–1180,2011.

Initial free carrier lifetimes extraction

Recovery of absorption and refractive index variation

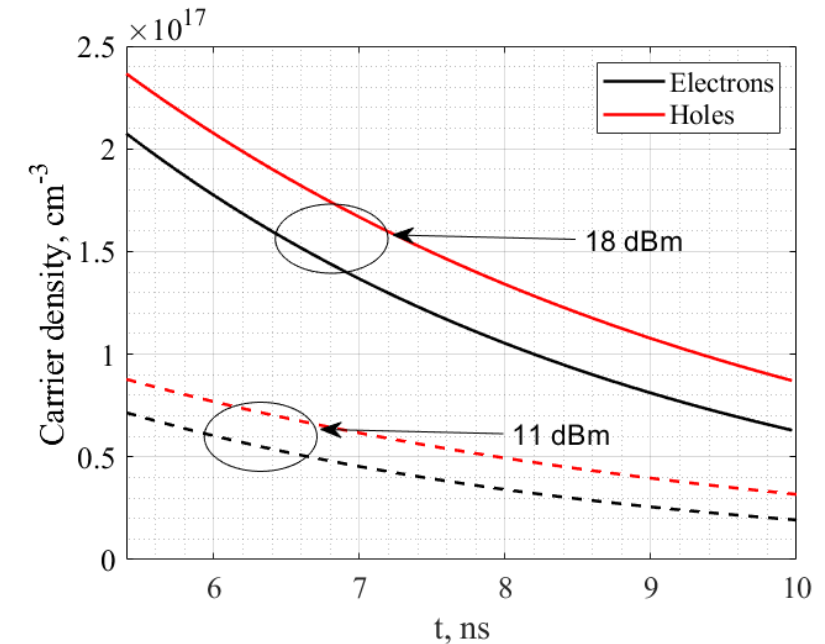


$$\Delta\alpha_{FCA} = \Gamma(8.8 \cdot 10^{-21}n_e^{1.167} + 5.84 \cdot 10^{-20}p_e^{1.109})$$

$$\Delta n_{eff,FCD} = -\Gamma(5.4 \cdot 10^{-22}n_e^{1.011} + 1.53 \cdot 10^{-18}p_e^{0.838})$$



Electrons and holes carrier density in the ring



- The initial free carrier lifetimes of electrons and holes can be calculated by fitting the first ns with a single exponential.
- Good matching with the theory.

τ [ns]	Experiment	Theory
$\tau_{n,18dBm}$	3.6	2.7
$\tau_{p,18dBm}$	4.35	5
$\tau_{n,11dBm}$	1.15	0.83
$\tau_{p,11dBm}$	6.5	6.4



[1] Marco Novarese et al., *Opt. Express* vol. 30, 14341- 14357 (2022).